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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: 09/697,305

Confirmation No.: 4222

In re Application of:

Takaki YOSHIDA et al.

Group Art Unit: 2133

Filed: October 27, 2000

Examiner: Joseph D. Torres

For: FAULT DETECTING METHOD AND LAYOUT METHOD  
FOR SEMICONDUCTOR INTEGRATED CIRCUIT

PETITION UNDER 37 CFR §1.97(d)(2)

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Applicants hereby respectfully request consideration and entry of the Information Disclosure Statement filed contemporaneously herewith. The reference cited in the Information Disclosure Statement was cited in an Office Action in a corresponding Japanese patent application on September 21, 2004. The certification under Rule 97(e)(1) is filed herewith, as well as a check in the amount of \$180.00, pursuant to Rule 17(i)(1).

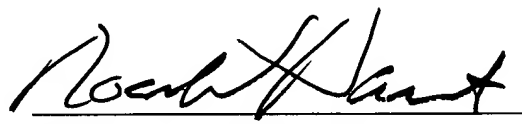
Serial No.: 09/697,305

Consideration and entry of the attached Information Disclosure  
Statement is respectfully requested.

Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

December 14, 2004  
Date

  
Roger W. Parkhurst  
Registration No. 25,177

RWP/mhs

Attachments: Check No. 18251 for \$180  
Certification Under 37 CFR §1.97(e)  
Information Disclosure Statement  
USPTO-1449  
Japanese Patent Appln. No. 09-080121

Attorney Docket No.: YMOR:186

PARKHURST & WENDEL, L.L.P.  
1421 Prince Street, Suite 210  
Alexandria, VA 22314-2805  
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PLEASE ACCEPT THIS AS  
AUTHORIZATION TO DEBIT  
OR CREDIT FEES TO  
DEP. ACCT. 16-0331  
PARKHURST & WENDEL



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FOR SEMICONDUCTOR INTEGRATED CIRCUIT

CERTIFICATION UNDER 37 CFR § 1.97(e)

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

☒ Each item of information contained in the Information Disclosure Statement filed herewith was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

OR

☐ No item of information in the Information Disclosure Statement filed, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR § 1.56(c) more

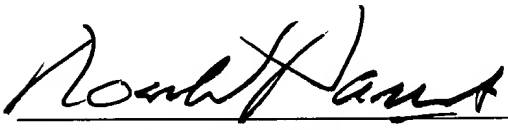
Serial No. 09/697,305

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Disclosure Statement.

Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

December 14, 2004  
Date

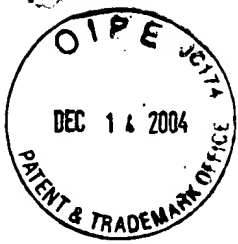
  
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Attachment:  
Information Disclosure Statement

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INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the U.S. Patent and Trademark Office is hereby directed to the reference listed on the attached Form PTO-1449. A copy of the reference listed on Form PTO-1449 is attached.

The attached reference, JP 9-80121 was cited in an Office Action dated September 21, 2004 in the corresponding Japanese Application No. 11-307872. The USPTO is directed thereto for a concise statement of possible relevance of the reference cited therein.


Serial No.: 09/697,305

The above information is presented so that the U.S. Patent and Trademark Office may, in the first instance, determine any materiality thereof to the claimed invention. See 37 CFR §1.104(a) and §1.106(b) concerning the USPTO duty to consider and use any such information. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

December 14, 2004  
Date

  
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